


Application No. 09/921,786
Attorney's Docket No. 000348-280
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IN THE ABSTRACT:

Kindly revise the Abstract which follows on a separate sheet:

ABSTRACT

 Method for real-time control of the fabrication of a thin-film structure comprising a substrate by ellipsometric measurement in which:

- variables directly linked to the ellipsometric ratio $\rho = \tan\Psi \exp(i\Delta)$ are measured; and
- the said variables are compared with reference values. The comparison relates to the length of the path traveled at a time t in the plane of the variables with respect to an initial point at time t_0 , for each layer participating in the thin-film structure.

Figure 2